

Search Notes

Application/Control No.

10/687,629

Examiner

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Applicant(s)/Patent under
Reexamination

INOUE, SATOSHI

Art Unit

2183

SEARCHED

Class	Subclass	Date	Examiner
712	33 225	05/30/07	DP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
west pgp uspat jpoabs derwent IEEE NPL IBM TD 710/22,23 711/112	5/30/2007	DP